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Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e600
Number of Cores/Bus Width	2 Core, 32-Bit
Speed	1.0GHz
Co-Processors/DSP	-
RAM Controllers	DDR, DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	1023-BCBGA, FCCBGA
Supplier Device Package	1023-FCCBGA (33x33)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mc8641dvu1000nc

2.1.3 Output Driver Characteristics

Table 3 provides information on the characteristics of the output driver strengths. The values are preliminary estimates.

Table 3. Output Drive Capability

Driver Type	Programmable Output Impedance (Ω)	Supply Voltage	Notes
DDR1 signal	18 36 (half strength mode)	$Dn_GV_{DD} = 2.5\text{ V}$	4, 9
DDR2 signal	18 36 (half strength mode)	$Dn_GV_{DD} = 1.8\text{ V}$	1, 5, 9
Local Bus signals	45 25	$OV_{DD} = 3.3\text{ V}$	2, 6
eTSEC/10/100 signals	45	$T/LV_{DD} = 3.3\text{ V}$	6
	30	$T/LV_{DD} = 2.5\text{ V}$	6
DUART, DMA, Multiprocessor Interrupts, System Control & Clocking, Debug, Test, Power management, JTAG and Miscellaneous I/O voltage	45	$OV_{DD} = 3.3\text{ V}$	6
I ² C	150	$OV_{DD} = 3.3\text{ V}$	7
SRIO, PCI Express	100	$SV_{DD} = 1.1/1.05\text{ V}$	3, 8

Notes:

1. See the DDR Control Driver registers in the MPC8641D reference manual for more information.
2. Only the following local bus signals have programmable drive strengths: LALE, LAD[0:31], LDP[0:3], LA[27:31], LCKE, LCS[1:2], LWE[0:3], LGPL1, LGPL2, LGPL3, LGPL4, LGPL5, LCLK[0:2]. The other local bus signals have a fixed drive strength of 45 Ω . See the POR Impedance Control register in the MPC8641D reference manual for more information about local bus signals and their drive strength programmability.
3. See [Section 17, "Signal Listings,"](#) for details on resistor requirements for the calibration of $SDn_IMP_CAL_TX$ and $SDn_IMP_CAL_RX$ transmit and receive signals.
4. Stub Series Terminated Logic (SSTL-25) type pins.
5. Stub Series Terminated Logic (SSTL-18) type pins.
6. Low Voltage Transistor-Transistor Logic (LVTTL) type pins.
7. Open Drain type pins.
8. Low Voltage Differential Signaling (LVDS) type pins.
9. The drive strength of the DDR interface in half strength mode is at $T_j = 105^\circ\text{C}$ and at Dn_GV_{DD} (min).

2.2 Power Up/Down Sequence

The MPC8641 requires its power rails to be applied in a specific sequence in order to ensure proper device operation.

NOTE

The recommended maximum ramp up time for power supplies is 20 milliseconds.

The chronological order of power up is as follows:

1. All power rails other than DDR I/O (Dn_GV_{DD} , and Dn_MV_{REF}).

NOTE

There is no required order sequence between the individual rails for this item (# 1). However, V_{DD_PLAT} , AV_{DD_PLAT} rails must reach 90% of their recommended value before the rail for Dn_GV_{DD} , and Dn_MV_{REF} (in next step) reaches 10% of their recommended value. AV_{DD} type supplies must be delayed with respect to their source supplies by the RC time constant of the PLL filter circuit described in [Section 20.2.1, “PLL Power Supply Filtering.”](#)

2. Dn_GV_{DD} , Dn_MV_{REF}

NOTE

It is possible to leave the related power supply (Dn_GV_{DD} , Dn_MV_{REF}) turned off at reset for a DDR port that will not be used. Note that these power supplies can only be powered up again at reset for functionality to occur on the DDR port.

3. SYSCLK

The recommended order of power down is as follows:

1. Dn_GV_{DD} , Dn_MV_{REF}
2. All power rails other than DDR I/O (Dn_GV_{DD} , Dn_MV_{REF}).

NOTE

SYSCLK may be powered down simultaneous to either of item # 1 or # 2 in the power down sequence. Beyond this, the power supplies may power down simultaneously if the preservation of DDRn memory is not a concern.

See [Figure 3](#) for more details on the Power and Reset Sequencing details.

3 Power Characteristics

The power dissipation for the dual core MPC8641D device is shown in [Table 4](#).

Table 4. MPC8641D Power Dissipation (Dual Core)

Power Mode	Core Frequency (MHz)	Platform Frequency (MHz)	V _{DD_Coren} , V _{DD_PLAT} (Volts)	Junction Temperature	Power (Watts)	Notes
Typical	1500 MHz	600 MHz	1.1 V	65 °C	32.1	1, 2
Thermal				105 °C	43.4	1, 3
Maximum					49.9	1, 4
Typical	1333 MHz	533 MHz	1.05 V	65 °C	23.9	1, 2
Thermal				105 °C	30.0	1, 3
Maximum					34.1	1, 4
Typical	1250 MHz	500 MHz	1.05 V	65 °C	23.9	1, 2
Thermal				105 °C	30.0	1, 3
Maximum					34.1	1, 4
Typical	1000 MHz	400 MHz	1.05 V	65 °C	23.9	1, 2
Thermal				105 °C	30.0	1, 3
Maximum					34.1	1, 4
Typical	1000 MHz	500 MHz	0.95 V, 1.05 V	65 °C	16.2	1, 2, 5
Thermal				105 °C	21.8	1, 3, 5
Maximum					25.0	1, 4, 5

Notes:

1. These values specify the power consumption at nominal voltage and apply to all valid processor bus frequencies and configurations. The values do not include power dissipation for I/O supplies.
2. Typical power is an average value measured at the nominal recommended core voltage (V_{DD_Coren}) and 65°C junction temperature (see [Table 2](#)) while running the Dhrystone 2.1 benchmark and achieving 2.3 Dhrystone MIPs/MHz with one core at 100% efficiency and the second core at 65% efficiency.
3. Thermal power is the average power measured at nominal core voltage (V_{DD_Coren}) and maximum operating junction temperature (see [Table 2](#)) while running the Dhrystone 2.1 benchmark and achieving 2.3 Dhrystone MIPs/MHz on both cores and a typical workload on platform interfaces.
4. Maximum power is the maximum power measured at nominal core voltage (V_{DD_Coren}) and maximum operating junction temperature (see [Table 2](#)) while running a test which includes an entirely L1-cache-resident, contrived sequence of instructions which keep all the execution units maximally busy on both cores.
5. These power numbers are for Part Number MC8641Dxx1000NX only. V_{DD_Coren} = 0.95 V and V_{DD_PLAT} = 1.05 V.

Table 28. GMII Transmit AC Timing Specifications (continued)

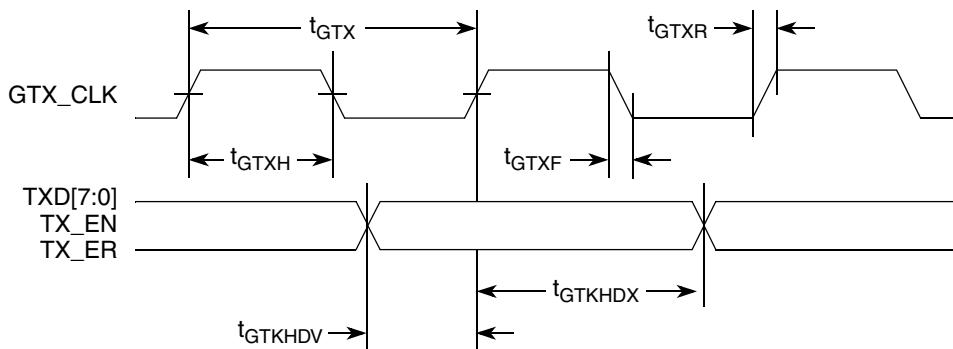
At recommended operating conditions with L/TV_{DD} of 3.3 V ± 5% and 2.5 V ± 5%.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
GTX_CLK data clock fall time (80%-20%)	t _{GTXF} ²	—	—	1.0	ns

Notes:

1. The symbols used for timing specifications herein follow the pattern t_{(first two letters of functional block)(signal)(state) (reference)(state)} for inputs and t_{(first two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{GTKHDX} symbolizes GMII transmit timing (GT) with respect to the t_{GT} clock reference (K) going to the high state (H) relative to the time date input signals (D) reaching the valid state (V) to state or setup time. Also, t_{GTKHDX} symbolizes GMII transmit timing (GT) with respect to the t_{GT} clock reference (K) going to the high state (H) relative to the time date input signals (D) going invalid (X) or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{GT} represents the GMII(G) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. Guaranteed by design.

Figure 10 shows the GMII transmit AC timing diagram.


Figure 10. GMII Transmit AC Timing Diagram

8.2.2.2 GMII Receive AC Timing Specifications

Table 29 provides the GMII receive AC timing specifications.

Table 29. GMII Receive AC Timing Specifications

At recommended operating conditions with L/TV_{DD} of 3.3 V ± 5% and 2.5 V ± 5%.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
RX_CLK clock period	t _{GRX} ³	—	8.0	—	ns
RX_CLK duty cycle	t _{GRXH} /t _{GRX}	40	—	60	ns
RXD[7:0], RX_DV, RX_ER setup time to RX_CLK	t _{GRDVKH}	2.0	—	—	ns
RXD[7:0], RX_DV, RX_ER hold time to RX_CLK	t _{GRDXKH}	0.5	—	—	ns
RX_CLK clock rise time (20%-80%)	t _{GRXR} ²	—	—	1.0	ns

8.2.4.2 TBI Receive AC Timing Specifications

Table 33 provides the TBI receive AC timing specifications.

Table 33. TBI Receive AC Timing Specifications

At recommended operating conditions with L/TV_{DD} of 3.3 V ± 5% and 2.5 V ± 5%.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
PMA_RX_CLK[0:1] clock period	t_{TRX}^3	—	16.0	—	ns
PMA_RX_CLK[0:1] skew	t_{SKTRX}	7.5	—	8.5	ns
PMA_RX_CLK[0:1] duty cycle	t_{TRXH}/t_{TRXF}	40	—	60	%
RCG[9:0] setup time to rising PMA_RX_CLK	t_{TRDVKH}	2.5	—	—	ns
RCG[9:0] hold time to rising PMA_RX_CLK	t_{TRDXKH}	1.5	—	—	ns
PMA_RX_CLK[0:1] clock rise time (20%-80%)	t_{TRXR}^2	0.7	—	2.4	ns
PMA_RX_CLK[0:1] clock fall time (80%-20%)	t_{TRXF}^2	0.7	—	2.4	ns

Note:

1. The symbols used for timing specifications herein follow the pattern of $t_{(first\ two\ letters\ of\ functional\ block)(signal)(state)\ (reference)(state)}$ for inputs and $t_{(first\ two\ letters\ of\ functional\ block)(reference)(state)(signal)(state)}$ for outputs. For example, t_{TRDVKH} symbolizes TBI receive timing (TR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{TRX} clock reference (K) going to the high (H) state or setup time. Also, t_{TRDXKH} symbolizes TBI receive timing (TR) with respect to the time data input signals (D) went invalid (X) relative to the t_{TRX} clock reference (K) going to the high (H) state. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{TRX} represents the TBI (T) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall). For symbols representing skews, the subscript is skew (SK) followed by the clock that is being skewed (TRX).
2. Guaranteed by design.
3. ±100 ppm tolerance on PMA_RX_CLK[0:1] frequency

Figure 17 shows the TBI receive AC timing diagram.

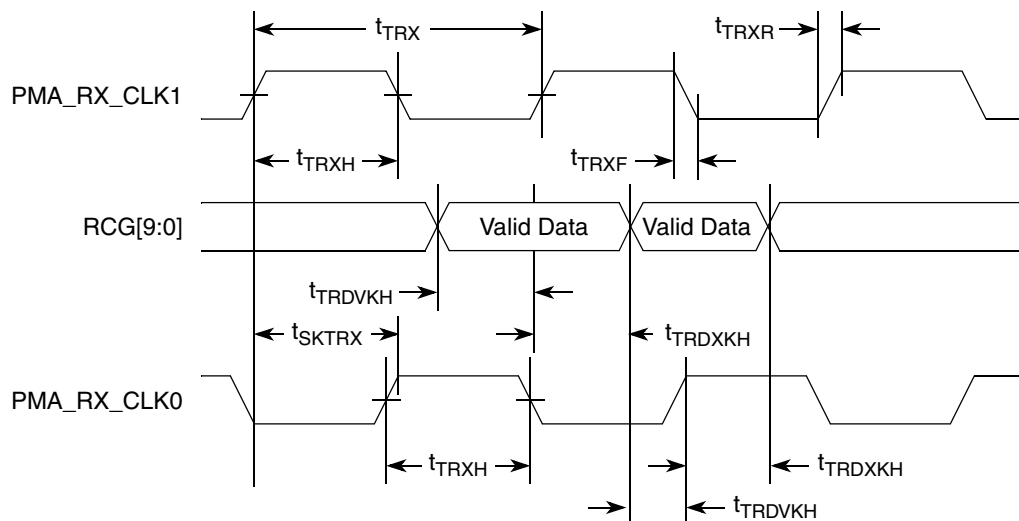


Figure 17. TBI Receive AC Timing Diagram

8.2.7 RMII AC Timing Specifications

This section describes the RMII transmit and receive AC timing specifications.

8.2.7.1 RMII Transmit AC Timing Specifications

The RMII transmit AC timing specifications are in [Table 36](#).

Table 36. RMII Transmit AC Timing Specifications

At recommended operating conditions with L/TV_{DD} of 3.3 V ± 5%.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
REF_CLK clock period	t_{RMT}	—	20.0	—	ns
REF_CLK duty cycle	t_{RMTH}/t_{RMT}	35	50	65	%
REF_CLK peak-to-peak jitter	t_{RMTJ}	—	—	250	ps
Rise time REF_CLK (20%–80%)	t_{RMTR}	1.0	—	2.0	ns
Fall time REF_CLK (80%–20%)	t_{RMTF}	1.0	—	2.0	ns
REF_CLK to RMII data TXD[1:0], TX_EN delay	t_{RMTDX}	1.0	—	10.0	ns

Note:

- The symbols used for timing specifications herein follow the pattern of $t_{(first\ two\ letters\ of\ functional\ block)(signal)(state)\ (reference)(state)}$ for inputs and $t_{(first\ two\ letters\ of\ functional\ block)(reference)(state)(signal)(state)}$ for outputs. For example, t_{MTKHDX} symbolizes MII transmit timing (MT) for the time t_{MTX} clock reference (K) going high (H) until data outputs (D) are invalid (X). Note that, in general, the clock reference symbol representation is based on two to three letters representing the clock of a particular functional. For example, the subscript of t_{MTX} represents the MII(M) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

[Figure 20](#) shows the RMII transmit AC timing diagram.

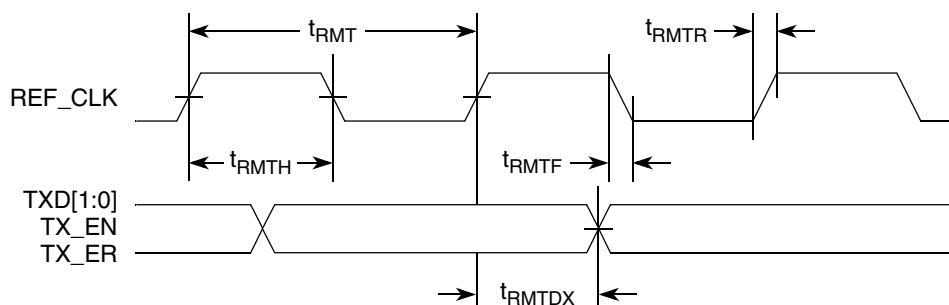


Figure 20. RMII Transmit AC Timing Diagram

Table 41. Local Bus Timing Parameters ($OV_{DD} = 3.3\text{ V}$)m - PLL Enabled (continued)

Parameter	Symbol ¹	Min	Max	Unit	Notes
Local bus clock to LALE assertion	$t_{LBKHOV4}$	—	2.3	ns	3
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKHOX1}$	0.7	—	ns	—
Output hold from local bus clock for LAD/LDP	$t_{LBKHOX2}$	0.7	—	ns	3
Local bus clock to output high Impedance (except LAD/LDP and LALE)	$t_{LBKHOZ1}$	—	2.5	ns	5
Local bus clock to output high impedance for LAD/LDP	$t_{LBKHOZ2}$	—	2.5	ns	5

Note:

1. The symbols used for timing specifications herein follow the pattern of $t_{(\text{First two letters of functional block})(\text{signal})(\text{state})}$ (reference)(state) for inputs and $t_{(\text{First two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one(1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to LSYNC_IN for PLL enabled and internal local bus clock for PLL bypass mode.
3. All signals are measured from $OV_{DD}/2$ of the rising edge of LSYNC_IN for PLL enabled or internal local bus clock for PLL bypass mode to $0.4 \times OV_{DD}$ of the signal in question for 3.3-V signaling levels.
4. Input timings are measured at the pin.
5. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
6. t_{LBOTOT} is a measurement of the minimum time between the negation of LALE and any change in LAD. t_{LBOTOT} is programmed with the LBCR[AHD] parameter.
7. Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at $BV_{DD}/2$.
8. Guaranteed by design.

Figure 25 provides the AC test load for the local bus.

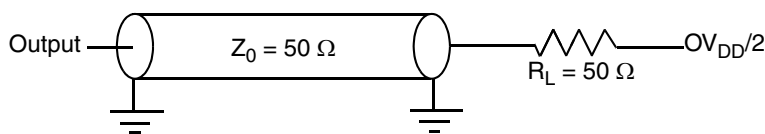


Figure 25. Local Bus AC Test Load

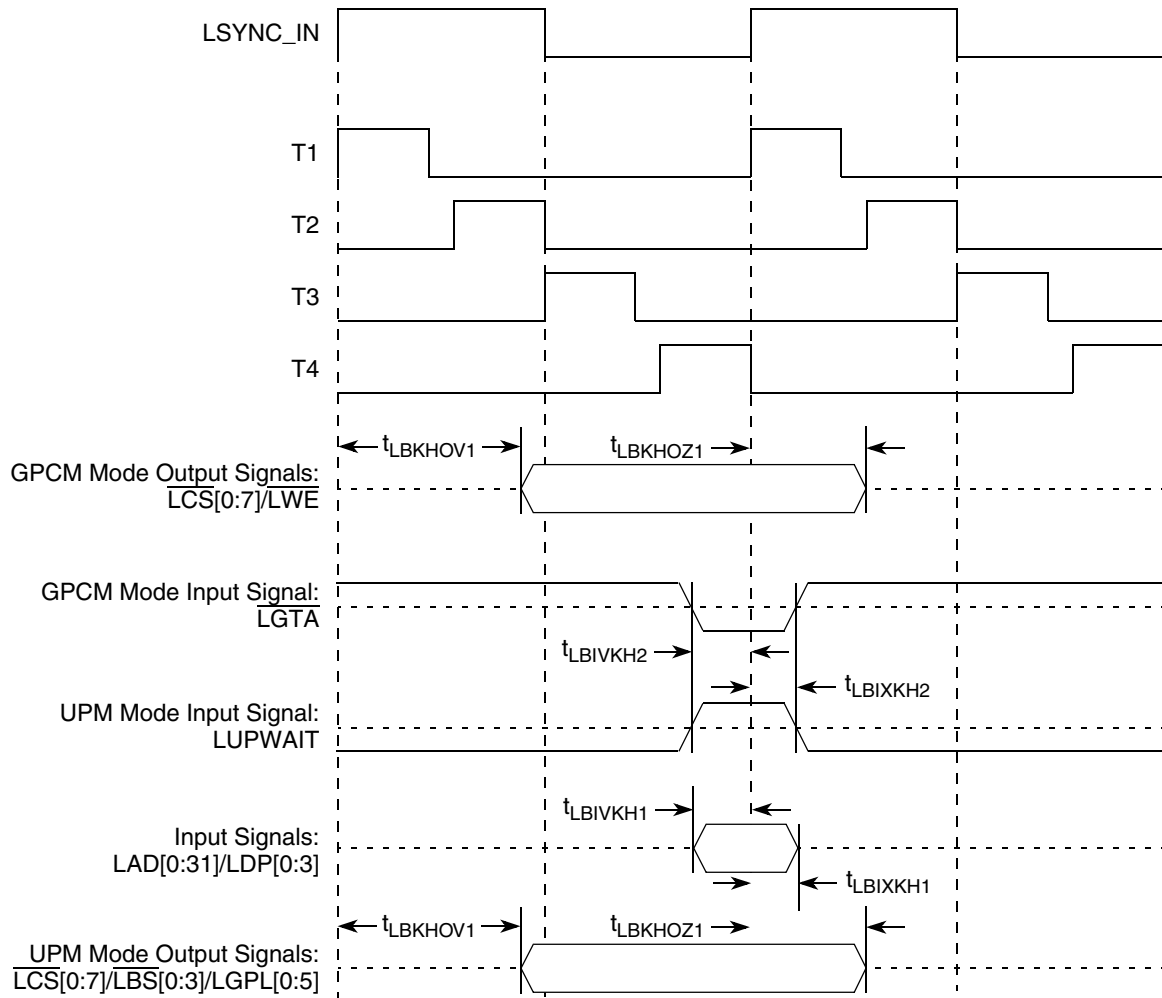


Figure 30. Local Bus Signals, GPCM/UPM Signals for $\text{LCRR}[\text{CLKDIV}] = 4$ or 8 (clock ratio of 8 or 16) (PLL Enabled)

Figure 34 provides the $\overline{\text{TRST}}$ timing diagram.

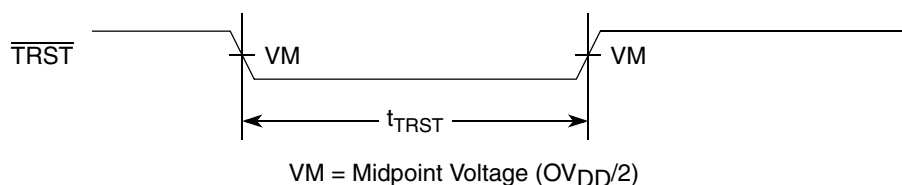


Figure 34. $\overline{\text{TRST}}$ Timing Diagram

Figure 35 provides the boundary-scan timing diagram.

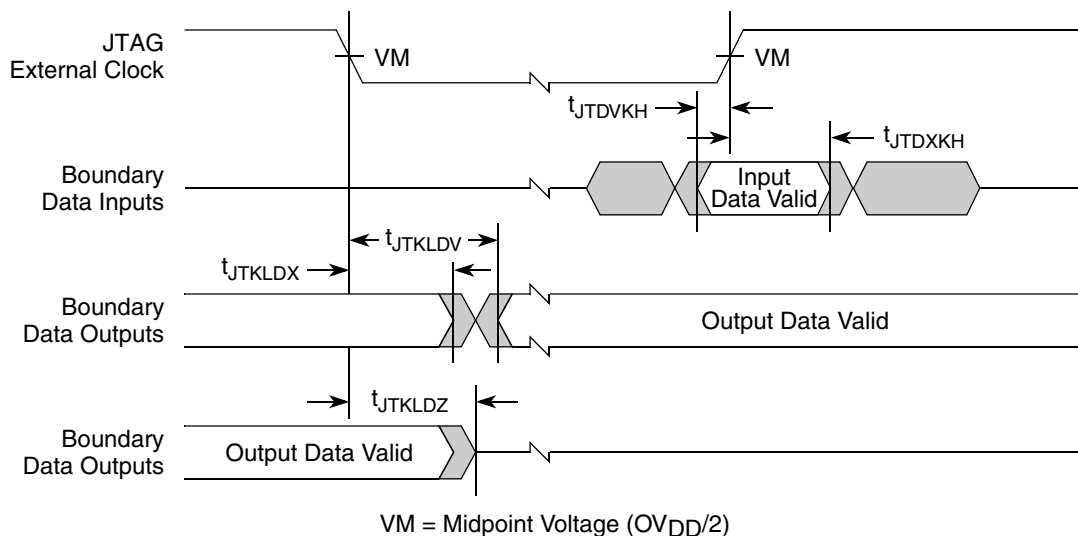


Figure 35. Boundary-Scan Timing Diagram

12 I²C

This section describes the DC and AC electrical characteristics for the I²C interfaces of the MPC8641.

12.1 I²C DC Electrical Characteristics

Table 45 provides the DC electrical characteristics for the I²C interfaces.

Table 45. I²C DC Electrical Characteristics

At recommended operating conditions with OV_{DD} of $3.3 \text{ V} \pm 5\%$.

Parameter	Symbol	Min	Max	Unit	Notes
Input high voltage level	V_{IH}	$0.7 \times \text{OV}_{\text{DD}}$	$\text{OV}_{\text{DD}} + 0.3$	V	—
Input low voltage level	V_{IL}	-0.3	$0.3 \times \text{OV}_{\text{DD}}$	V	—
Low level output voltage	V_{OL}	0	$0.2 \times \text{OV}_{\text{DD}}$	V	1
Pulse width of spikes which must be suppressed by the input filter	t_{i2KHKL}	0	50	ns	2
Input current each I/O pin (input voltage is between $0.1 \times \text{OV}_{\text{DD}}$ and $0.9 \times \text{OV}_{\text{DD}}$ (max))	I_{I}	-10	10	μA	3

Table 45. I²C DC Electrical Characteristics (continued)

At recommended operating conditions with OV_{DD} of 3.3 V ± 5%.

Parameter	Symbol	Min	Max	Unit	Notes
Capacitance for each I/O pin	C _I	—	10	pF	—

Notes:

1. Output voltage (open drain or open collector) condition = 3 mA sink current.
2. Refer to the *MPC8641 Integrated Host Processor Reference Manual* for information on the digital filter used.
3. I/O pins will obstruct the SDA and SCL lines if OV_{DD} is switched off.

12.2 I²C AC Electrical Specifications

Table 46 provides the AC timing parameters for the I²C interfaces.

Table 46. I²C AC Electrical Specifications

All values refer to V_{IH} (min) and V_{IL} (max) levels (see Table 45).

Parameter	Symbol ¹	Min	Max	Unit
SCL clock frequency	f _{I2C}	0	400	kHz
Low period of the SCL clock	t _{I2CL} ⁴	1.3	—	μs
High period of the SCL clock	t _{I2CH} ⁴	0.6	—	μs
Setup time for a repeated START condition	t _{I2SVKH} ⁴	0.6	—	μs
Hold time (repeated) START condition (after this period, the first clock pulse is generated)	t _{I2SXKL} ⁴	0.6	—	μs
Data setup time	t _{I2DVKH} ⁴	100	—	ns
Data input hold time: CBUS compatible masters I ² C bus devices	t _{I2DXKL}	— 0 ²	— —	μs
Rise time of both SDA and SCL signals	t _{I2CR}	20 + 0.1 C _B ⁵	300	ns
Fall time of both SDA and SCL signals	t _{I2CF}	20 + 0.1 C _b ⁵	300	ns
Data output delay time	t _{I2OVKL}	—	0.9 ³	μs
Set-up time for STOP condition	t _{I2PVKH}	0.6	—	μs
Bus free time between a STOP and START condition	t _{I2KHDX}	1.3	—	μs
Noise margin at the LOW level for each connected device (including hysteresis)	V _{NL}	0.1 × OV _{DD}	—	V

Table 46. I²C AC Electrical Specifications (continued)

All values refer to V_{IH} (min) and V_{IL} (max) levels (see Table 45).

Parameter	Symbol ¹	Min	Max	Unit
Noise margin at the HIGH level for each connected device (including hysteresis)	V _{NH}	0.2 × OV _{DD}	—	V

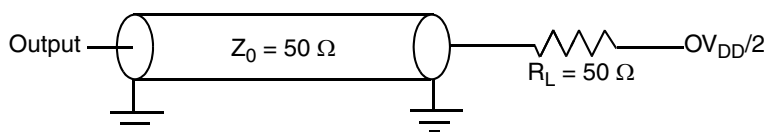
Note:

- The symbols used for timing specifications herein follow the pattern of t_{(first two letters of functional block)(signal)(state) (reference)(state)} for inputs and t_{(first two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{I2DV_{KH}} symbolizes I²C timing (I2) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. Also, t_{I2SX_{KL}} symbolizes I²C timing (I2) for the time that the data with respect to the start condition (S) went invalid (X) relative to the t_{I2C} clock reference (K) going to the low (L) state or hold time. Also, t_{I2PV_{KH}} symbolizes I²C timing (I2) for the time that the data with respect to the stop condition (P) reaching the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
- As a transmitter, the MPC8641 provides a delay time of at least 300 ns for the SDA signal (referred to the V_{IHmin} of the SCL signal) to bridge the undefined region of the falling edge of SCL to avoid unintended generation of Start or Stop condition. When MPC8641 acts as the I²C bus master while transmitting, MPC8641 drives both SCL and SDA. As long as the load on SCL and SDA are balanced, MPC8641 would not cause unintended generation of Start or Stop condition. Therefore, the 300 ns SDA output delay time is not a concern. If, under some rare condition, the 300 ns SDA output delay time is required for MPC8641 as transmitter, the following setting is recommended for the FDR bit field of the I2CFDR register to ensure both the desired I²C SCL clock frequency and SDA output delay time are achieved, assuming that the desired I²C SCL clock frequency is 400 KHz and the Digital Filter Sampling Rate Register (I2CDFSRR) is programmed with its default setting of 0x10 (decimal 16):

I ² C Source Clock Frequency	333 MHz	266 MHz	200 MHz	133 MHz
FDR Bit Setting	0x2A	0x05	0x26	0x00
Actual FDR Divider Selected	896	704	512	384
Actual I ² C SCL Frequency Generated	371 KHz	378 KHz	390 KHz	346 KHz

For the detail of I²C frequency calculation, refer to the application note AN2919 “Determining the I²C Frequency Divider Ratio for SCL”. Note that the I²C Source Clock Frequency is half of the MPX clock frequency for MPC8641.
- The maximum t_{I2DX_{KL}} has only to be met if the device does not stretch the LOW period (t_{I2CL}) of the SCL signal.
- Guaranteed by design.
- C_B = capacitance of one bus line in pF.

Figure 32 provides the AC test load for the I²C.


Figure 36. I²C AC Test Load

The diagram illustrates the timing relationships for the I2C bus protocol. It shows two signal lines: SDA (Serial Data) and SCL (Serial Clock). The diagram is divided into four sections labeled S, Sr, P, and S, representing different states or transitions. Key timing parameters are indicated by arrows and labels:

- t_{12CF} : Time from SCL falling edge to SDA falling edge.
- t_{12CL} : Time from SCL rising edge to SDA rising edge.
- t_{12SXKL} : Time from SCL rising edge to SDA rising edge (specific to the S state).
- t_{12CH} : Time from SCL falling edge to SDA falling edge (specific to the S state).
- t_{12DXKL} : Time from SCL rising edge to SDA rising edge (specific to the S state).
- t_{12DVKH} : Time from SCL falling edge to SDA falling edge (specific to the S state).
- t_{12SXKL} : Time from SCL rising edge to SDA rising edge (specific to the Sr state).
- t_{12SVKH} : Time from SCL falling edge to SDA falling edge (specific to the Sr state).
- t_{12KHKL} : Time from SCL rising edge to SDA rising edge (specific to the P state).
- t_{12PVKH} : Time from SCL falling edge to SDA falling edge (specific to the P state).
- t_{12CR} : Time from SCL rising edge to SDA rising edge (specific to the S state).
- t_{12CF} : Time from SCL falling edge to SDA falling edge (specific to the S state).

Figure 37. I²C Bus AC Timing Diagram

To illustrate these definitions using real values, consider the case of a CML (Current Mode Logic) transmitter that has a common mode voltage of 2.25 V and each of its outputs, TD and $\overline{\text{TD}}$, has a swing that goes between 2.5 V and 2.0 V. Using these values, the peak-to-peak voltage swing of each signal (TD or $\overline{\text{TD}}$) is 500 mV p-p, which is referred as the single-ended swing for each signal. In this example, since the differential signaling environment is fully symmetrical, the transmitter output's differential swing (V_{OD}) has the same amplitude as each signal's single-ended swing. The differential output signal ranges between 500 mV and -500 mV, in other words, V_{OD} is 500 mV in one phase and -500 mV in the other phase. The peak differential voltage (V_{DIFFp}) is 500 mV. The peak-to-peak differential voltage ($V_{\text{DIFFp-p}}$) is 1000 mV p-p.

13.2 SerDes Reference Clocks

The SerDes reference clock inputs are applied to an internal PLL whose output creates the clock used by the corresponding SerDes lanes. The SerDes reference clocks inputs are SDn_REF_CLK and $\overline{\text{SDn_REF_CLK}}$ for PCI Express and Serial RapidIO.

The following sections describe the SerDes reference clock requirements and some application information.

13.2.1 SerDes Reference Clock Receiver Characteristics

Figure 39 shows a receiver reference diagram of the SerDes reference clocks.

- The supply voltage requirements for $\text{XV}_{\text{DD_SRDSn}}$ are specified in Table 1 and Table 2.
- SerDes Reference Clock Receiver Reference Circuit Structure
 - The SDn_REF_CLK and $\overline{\text{SDn_REF_CLK}}$ are internally AC-coupled differential inputs as shown in Figure 39. Each differential clock input (SDn_REF_CLK or $\overline{\text{SDn_REF_CLK}}$) has a 50- Ω termination to SGND followed by on-chip AC-coupling.
 - The external reference clock driver must be able to drive this termination.
 - The SerDes reference clock input can be either differential or single-ended. Refer to the Differential Mode and Single-ended Mode description below for further detailed requirements.
- The maximum average current requirement that also determines the common mode voltage range
 - When the SerDes reference clock differential inputs are DC coupled externally with the clock driver chip, the maximum average current allowed for each input pin is 8 mA. In this case, the exact common mode input voltage is not critical as long as it is within the range allowed by the maximum average current of 8 mA (refer to the following bullet for more detail), since the input is AC-coupled on-chip.
 - This current limitation sets the maximum common mode input voltage to be less than 0.4 V ($0.4 \text{ V}/50 = 8 \text{ mA}$) while the minimum common mode input level is 0.1 V above SGND. For example, a clock with a 50/50 duty cycle can be produced by a clock driver with output driven by its current source from 0 mA to 16 mA (0–0.8 V), such that each phase of the differential input has a single-ended swing from 0 V to 800 mV with the common mode voltage at 400 mV.
 - If the device driving the SDn_REF_CLK and $\overline{\text{SDn_REF_CLK}}$ inputs cannot drive 50 Ω to SGND DC, or it exceeds the maximum input current limitations, then it must be AC-coupled off-chip.

13.2.3 Interfacing With Other Differential Signaling Levels

With on-chip termination to SGND, the differential reference clocks inputs are HCSL (High-Speed Current Steering Logic) compatible DC-coupled.

Many other low voltage differential type outputs like LVDS (Low Voltage Differential Signaling) can be used but may need to be AC-coupled due to the limited common mode input range allowed (100 to 400 mV) for DC-coupled connection.

LVPECL outputs can produce signal with too large amplitude and may need to be DC-biased at clock driver output first, then followed with series attenuation resistor to reduce the amplitude, in addition to AC-coupling.

NOTE

Figure 43 to Figure 46 below are for conceptual reference only. Due to the fact that clock driver chip's internal structure, output impedance and termination requirements are different between various clock driver chip manufacturers, it is very possible that the clock circuit reference designs provided by clock driver chip vendor are different from what is shown below. They might also vary from one vendor to the other. Therefore, Freescale Semiconductor can neither provide the optimal clock driver reference circuits, nor guarantee the correctness of the following clock driver connection reference circuits. The system designer is recommended to contact the selected clock driver chip vendor for the optimal reference circuits with the MPC8641D SerDes reference clock receiver requirement provided in this document.

14.1 DC Requirements for PCI Express SDn_REF_CLK and SDn_REF_CLK

For more information, see [Section 13.2, “SerDes Reference Clocks.”](#)

14.2 AC Requirements for PCI Express SerDes Clocks

[Table 48](#) lists AC requirements.

Table 48. SDn_REF_CLK and SDn_REF_CLK AC Requirements

Symbol	Parameter Description	Min	Typical	Max	Units	Notes
t_{REF}	REFCLK cycle time	—	10	—	ns	—
t_{REFCJ}	REFCLK cycle-to-cycle jitter. Difference in the period of any two adjacent REFCLK cycles	—	—	100	ps	—
t_{REFPJ}	Phase jitter. Deviation in edge location with respect to mean edge location	–50	—	50	ps	—

14.3 Clocking Dependencies

The ports on the two ends of a link must transmit data at a rate that is within 600 parts per million (ppm) of each other at all times. This is specified to allow bit rate clock sources with a ± 300 ppm tolerance.

14.4 Physical Layer Specifications

The following is a summary of the specifications for the physical layer of PCI Express on this device. For further details as well as the specifications of the Transport and Data Link layer please use the PCI EXPRESS Base Specification. REV. 1.0a document.

14.4.1 Differential Transmitter (TX) Output

[Table 49](#) defines the specifications for the differential output at all transmitters (TXs). The parameters are specified at the component pins.

Table 49. Differential Transmitter (TX) Output Specifications

Symbol	Parameter	Min	Nom	Max	Units	Comments
UI	Unit Interval	399.88	400	400.12	ps	Each UI is $400\text{ ps} \pm 300\text{ ppm}$. UI does not account for Spread Spectrum Clock dictated variations. See Note 1.
$V_{TX-DIFFp-p}$	Differential Peak-to-Peak Output Voltage	0.8	—	1.2	V	$V_{TX-DIFFp-p} = 2 \cdot V_{TX-D+} - V_{TX-D-} $ See Note 2.
$V_{TX-DE-RATIO}$	De-Emphasized Differential Output Voltage (Ratio)	–3.0	–3.5	–4.0	dB	Ratio of the $V_{TX-DIFFp-p}$ of the second and following bits after a transition divided by the $V_{TX-DIFFp-p}$ of the first bit after a transition. See Note 2.

14.4.2 Transmitter Compliance Eye Diagrams

The TX eye diagram in Figure 50 is specified using the passive compliance/test measurement load (see Figure 52) in place of any real PCI Express interconnect + RX component.

There are two eye diagrams that must be met for the transmitter. Both eye diagrams must be aligned in time using the jitter median to locate the center of the eye diagram. The different eye diagrams will differ in voltage depending whether it is a transition bit or a de-emphasized bit. The exact reduced voltage level of the de-emphasized bit will always be relative to the transition bit.

The eye diagram must be valid for any 250 consecutive UIs.

A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The eye diagram is created using all edges of the 250 consecutive UI in the center of the 3500 UI used for calculating the TX UI.

NOTE

It is recommended that the recovered TX UI is calculated using all edges in the 3500 consecutive UI interval with a fit algorithm using a minimization merit function (that is, least squares and median deviation fits).

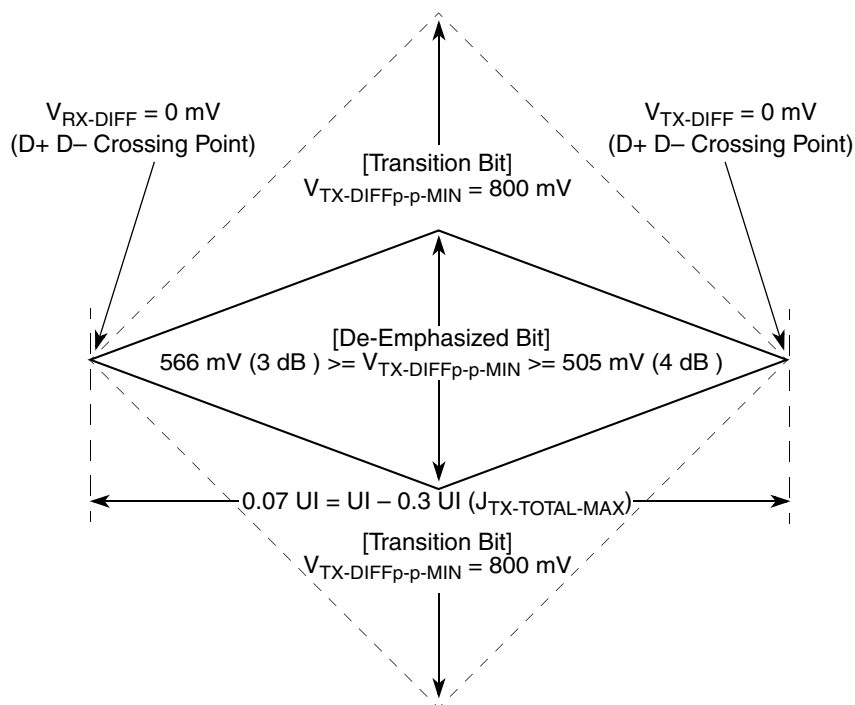


Figure 50. Minimum Transmitter Timing and Voltage Output Compliance Specifications

provide additional margin to adequately compensate for the degraded minimum Receiver eye diagram (shown in [Figure 51](#)) expected at the input Receiver based on some adequate combination of system simulations and the Return Loss measured looking into the RX package and silicon. The RX eye diagram must be aligned in time using the jitter median to locate the center of the eye diagram.

The eye diagram must be valid for any 250 consecutive UIs.

A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The eye diagram is created using all edges of the 250 consecutive UI in the center of the 3500 UI used for calculating the TX UI.

NOTE

The reference impedance for return loss measurements is 50Ω to ground for both the D+ and D- line (that is, as measured by a Vector Network Analyzer with 50Ω probes—see [Figure 52](#)). Note that the series capacitors, C_{TX} , are optional for the return loss measurement.

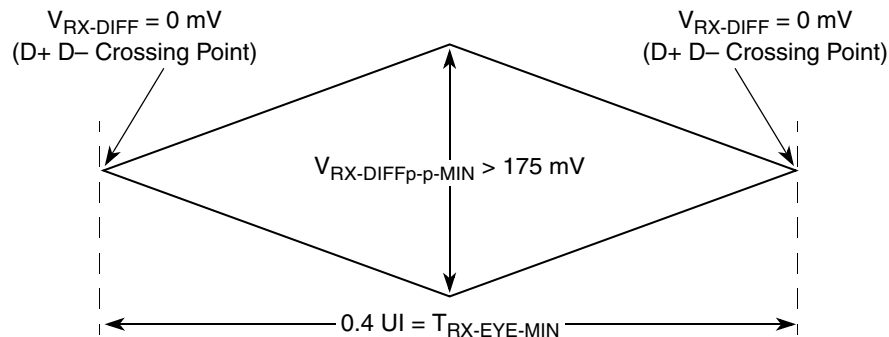


Figure 51. Minimum Receiver Eye Timing and Voltage Compliance Specification

14.5.1 Compliance Test and Measurement Load

The AC timing and voltage parameters must be verified at the measurement point, as specified within 0.2 inches of the package pins, into a test/measurement load shown in [Figure 52](#).

NOTE

The allowance of the measurement point to be within 0.2 inches of the package pins is meant to acknowledge that package/board routing may benefit from D+ and D- not being exactly matched in length at the package pin boundary.

Table 58. Transmitter Differential Output Eye Diagram Parameters

Transmitter Type	V _{DIFFmin} (mV)	V _{DIFFmax} (mV)	A (UI)	B (UI)
1.25 GBaud short range	250	500	0.175	0.39
1.25 GBaud long range	400	800	0.175	0.39
2.5 GBaud short range	250	500	0.175	0.39
2.5 GBaud long range	400	800	0.175	0.39
3.125 GBaud short range	250	500	0.175	0.39
3.125 GBaud long range	400	800	0.175	0.39

15.7 Receiver Specifications

LP-Serial receiver electrical and timing specifications are stated in the text and tables of this section.

Receiver input impedance shall result in a differential return loss better than 10 dB and a common mode return loss better than 6 dB from 100 MHz to (0.8)*(Baud Frequency). This includes contributions from on-chip circuitry, the chip package and any off-chip components related to the receiver. AC coupling components are included in this requirement. The reference impedance for return loss measurements is 100 Ohm resistive for differential return loss and 25 Ohm resistive for common mode.

Table 59. Receiver AC Timing Specifications—1.25 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Differential Input Voltage	V _{IN}	200	1600	mV p-p	Measured at receiver
Deterministic Jitter Tolerance	J _D	0.37	—	UI p-p	Measured at receiver
Combined Deterministic and Random Jitter Tolerance	J _{DR}	0.55	—	UI p-p	Measured at receiver
Total Jitter Tolerance ¹	J _T	0.65	—	UI p-p	Measured at receiver
Multiple Input Skew	S _{MI}	—	24	ns	Skew at the receiver input between lanes of a multilane link
Bit Error Rate	BER	—	10 ⁻¹²	—	—
Unit Interval	UI	800	800	ps	+/- 100 ppm

Note:

1. Total jitter is composed of three components, deterministic jitter, random jitter and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of [Figure 55](#). The sinusoidal jitter component is included to ensure margin for low frequency jitter, wander, noise, crosstalk and other variable system effects.

20 System Design Information

This section provides electrical and thermal design recommendations for successful application of the MPC8641.

20.1 System Clocking

This device includes six PLLs, as follows:

1. The platform PLL generates the platform clock from the externally supplied SYSCLK input. The frequency ratio between the platform and SYSCLK is selected using the platform PLL ratio configuration bits as described in [Section 18.2, “MPX to SYSCLK PLL Ratio.”](#)
2. The dual e600 Core PLLs generate the e600 clock from the externally supplied input.
3. The local bus PLL generates the clock for the local bus.
4. There are two internal PLLs for the SerDes block.

20.2 Power Supply Design and Sequencing

20.2.1 PLL Power Supply Filtering

Each of the PLLs listed above is provided with power through independent power supply pins.

There are a number of ways to reliably provide power to the PLLs, but the recommended solution is to provide independent filter circuits per PLL power supply as illustrated in [Figure 64](#), one to each of the AV_{DD} type pins. By providing independent filters to each PLL the opportunity to cause noise injection from one PLL to the other is reduced.

This circuit is intended to filter noise in the PLLs resonant frequency range from a 500 kHz to 10 MHz range. It should be built with surface mount capacitors with minimum Effective Series Inductance (ESL). Consistent with the recommendations of Dr. Howard Johnson in *High Speed Digital Design: A Handbook of Black Magic* (Prentice Hall, 1993), multiple small capacitors of equal value are recommended over a single large value capacitor.

Each circuit should be placed as close as possible to the specific AV_{DD} type pin being supplied to minimize noise coupled from nearby circuits. It should be possible to route directly from the capacitors to the AV_{DD} type pin, which is on the periphery of the footprint, without the inductance of vias.

[Figure 63](#) and [Figure 64](#) show the PLL power supply filter circuits for the platform and cores, respectively.

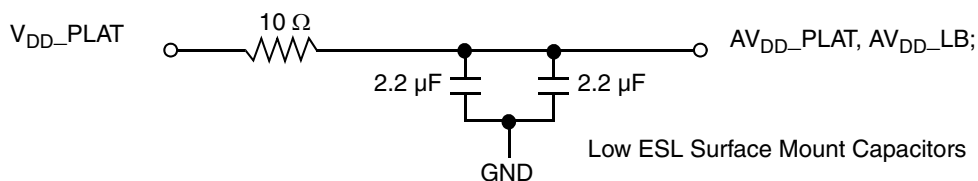
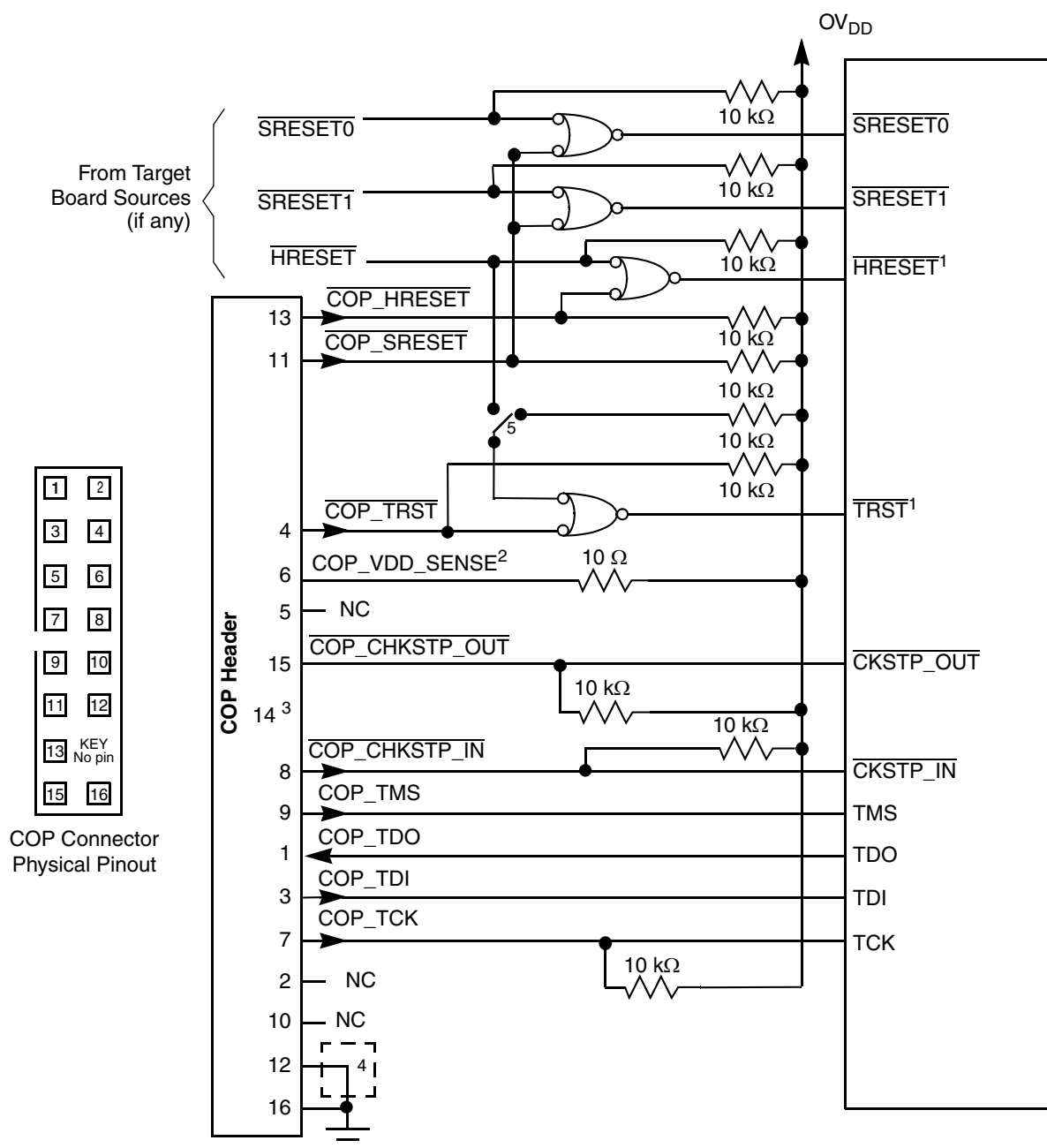


Figure 63. MPC8641 PLL Power Supply Filter Circuit (for platform and Local Bus)



Notes:

1. The COP port and target board should be able to independently assert $\overline{\text{HRESET}}$ and $\overline{\text{TRST}}$ to the processor in order to fully control the processor as shown here.
2. Populate this with a 10 Ω resistor for short-circuit/current-limiting protection.
3. The KEY location (pin 14) is not physically present on the COP header.
4. Although pin 12 is defined as a No-Connect, some debug tools may use pin 12 as an additional GND pin for improved signal integrity.
5. This switch is included as a precaution for BSDL testing. The switch should be open during BSDL testing to avoid accidentally asserting the $\overline{\text{TRST}}$ line. If BSDL testing is not being performed, this switch should be closed or removed.

Figure 68. JTAG/COP Interface Connection for one MPC8641 device